

TEKTRONIX

AWG610

The Tektronix AWG610 is a high-performance, single-channel arbitrary waveform generator belonging to the AWG600 Series. It features a maximum sampling rate of 2.6 GS/s and an 8-bit digital-to-analog converter (DAC) resolution. Optimized for high-speed signal simulation, the AWG610 is designed for disk drive testing, high-speed serial data communication, baseband/IF modulation, and various biomedical and transducer simulations. It incorporates a large 8M-point memory depth, real-time sequencing capability, and complementary analog outputs with options for direct or amplified signal paths. Control and programming are supported via standard GPIB, LAN, and RS-232-C interfaces.

SPECIFICATIONS

Waveform & Channel Specifications

Number of Channels	1
Digital-to-Analog Converter Resolution	8 bits
Maximum Sampling Rate	2.6 GS/s
Minimum Sampling Rate	50 kS/s

Analog Output Characteristics

Output Impedance	50 ohms
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Marker & Digital Outputs

Number of Marker Outputs	2
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Clock & Reference System

External Clock Input Impedance	50 ohms
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Trigger & Run Modes

Operating Modes	Continuous, Triggered, Gated, Enhanced
External Trigger Input Connector	BNC
External Trigger Input Impedance	1 kohm or 50 ohms

Sequencer Specifications

Maximum Sequence Steps	8,000 steps
Loop Counter Range	1 to 65,536 or Infinite

Physical & Environmental

Cooling Mechanism	Internal Fan Forced Air Cooling
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Mechanical, Standards & Compliance

Form Factor	Benchtop (rackmountable with optional kit)
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Analog Output

Low-Pass Filters	20 MHz, 50 MHz, 100 MHz, 200 MHz, Thru (selectable)
Analog Add Input Connector	BNC (rear panel)
Analog Add Input Impedance	50 Ω

Auxiliary Inputs/Outputs

Event Input Connector	BNC (rear panel)
Event Input Impedance	1 k Ω or 50 Ω (selectable)

TECHNOLOGY

Arbitrary Waveform Generation

APPLICATIONS

High-speed Mixed Signal Generation, Disk Drive Testing, Serial Data Communication, Baseband/IF Modulation Testing

Generated by SpecAtlasHub (specatlashub.com). Specifications are compiled from available sources and are subject to change — verify critical values against the manufacturer before purchase.